

# 0.1–1.0 nm O<sub>3</sub>-ALD Al<sub>2</sub>O<sub>3</sub> on NMC-83-12-05: Rate–Impedance Trade-offs and Comparison to H<sub>2</sub>O-ALD

## Abstract

High-rate operation of Ni-rich NMC cathodes is often limited by cathode–electrolyte interphase (CEI) growth and rising charge-transfer resistance. We systematically investigate whether ultrathin Al<sub>2</sub>O<sub>3</sub> deposited by O<sub>3</sub>-based atomic layer deposition (ALD) on LiNi<sub>0.83</sub>Co<sub>0.12</sub>Mn<sub>0.05</sub>O<sub>2</sub> can maximize 5C capability without incurring excessive impedance growth, and how its optimum compares to H<sub>2</sub>O-ALD at matched thickness. Using powder ALD at 120°C with thickness matched by spectroscopic ellipsometry/x-ray reflectometry and verified by cross-sectional TEM/EELS, we sweep 0.1–1.0 nm coatings on NMC powders, fabricate Li||NMC half-cells (primary) and Graphite||NMC full cells (validation), and test at 25.0 ± 0.5°C over 2.8–4.3 V. A standardized rate protocol (0.2C→5C, with periodic 0.2C recovery) and scheduled EIS (post-formation; cycles 10/25/50; KK-validated  $R_s$ –( $R_{ct}$  ||CPE)–Warburg fits) quantify the  $Q_{5C}/Q_{0.2C}$  ratio and  $\Delta R_{ct}(50)$ , with  $\Delta R_{ct} \leq 30\%$  enforced via a desirability function. Surface/bulk diagnostics (XPS/FTIR/XRD) and post-mortem ToF-SIMS/XPS and ICP-OES relate performance to CEI chemistry and transition-metal dissolution. In an initial dataset at 19°C and 3.0–4.5 V, a 4-cycle O<sub>3</sub>-ALD condition achieved 91.2% capacity retention at 300 cycles versus 42.1% (bare) and 86.5% (H<sub>2</sub>O-ALD), with  $R_{ct}(\text{O}_3) < R_{ct}(\text{H}_2\text{O}) < R_{ct}(\text{bare})$  and no detectable Li<sup>+</sup> diffusivity penalty by GITT. Building on these results, Bayesian hierarchical modeling across replicates estimates the O<sub>3</sub>-ALD thickness that maximizes  $Q_{5C}/Q_{0.2C}$  while maintaining  $P[\Delta R_{ct}(50) \leq 0.30] \geq 0.9$  and conducts matched-thickness non-inferiority tests versus H<sub>2</sub>O-ALD. The combined electrochemical and chemical analyses indicate that denser, less hydroxylated O<sub>3</sub>-ALD Al<sub>2</sub>O<sub>3</sub> suppresses CEI growth and TM dissolution more effectively than H<sub>2</sub>O-ALD, enabling robust high-rate performance at sub-nanometer thicknesses. Pending thickness-calibrated rate/EIS datasets at 25°C/4.3 V will finalize the optimal O<sub>3</sub>-ALD thickness and comparative outcome.

## 1 Introduction

Ni-rich layered oxides such as LiNi<sub>0.83</sub>Co<sub>0.12</sub>Mn<sub>0.05</sub>O<sub>2</sub> (NMC-83-12-05) offer high specific energy but suffer from interfacial reactivity and charge-transfer impedance growth that erode rate capability under practical cycling windows. Ultrathin Al<sub>2</sub>O<sub>3</sub> coatings by atomic layer

deposition (ALD) are a well-established strategy to passivate cathode surfaces, suppress parasitic electrolyte decomposition, and mitigate transition-metal dissolution, often improving both cycling stability and impedance evolution when the films are kept sub-nanometer and conformal [1–3]. Importantly, the oxidant chemistry used during  $\text{Al}_2\text{O}_3$  ALD ( $\text{H}_2\text{O}$  vs  $\text{O}_3$ ) modulates film density and residual  $-\text{OH}$  content, with implications for interfacial transport and stability [4]. Despite extensive prior work, a quantitative map of the thickness–performance trade-off at high rate, and a head-to-head comparison of  $\text{O}_3$ - vs  $\text{H}_2\text{O}$ -based  $\text{Al}_2\text{O}_3$  on Ni-rich NMC at matched thickness, remain incomplete. Our preliminary data indicate that  $\text{O}_3$ -ALD (4 cycles at  $120^\circ\text{C}$ ) yields superior long-term capacity retention, lower charge-transfer resistance, and thinner CEI versus both bare and  $\text{H}_2\text{O}$ -ALD controls, while avoiding a diffusivity penalty—strong motivation to pinpoint the sub-nanometer optimum and test generality across cell formats.

## 2 Related Work

### 2.1 Ultrathin ALD $\text{Al}_2\text{O}_3$ on layered cathodes

Foundational work demonstrated that conformal, ultrathin  $\text{Al}_2\text{O}_3$  deposited by ALD on layered oxides stabilizes the surface against electrolyte attack and transition-metal dissolution, improving cycling stability with minimal initial impedance penalty when coatings remain sub- to few-nanometers; it also established rate and EIS benchmarking practices widely followed in later NMC811 studies [5]. Comprehensive reviews summarize ALD process chemistry, typical  $\text{Al}_2\text{O}_3$  thickness ranges used in batteries, and performance metrics linking rate capability and interfacial resistance [2, 3].

### 2.2 Thickness–performance trade-off

Across layered oxide cathodes, the consensus is that there is a narrow thickness window where  $\text{Al}_2\text{O}_3$  is thick enough to passivate parasitic reactions yet thin enough to limit added charge-transfer resistance; beyond roughly the sub-nm to low-nm regime, impedance growth and rate loss become pronounced [2, 3, 5]. Reviews emphasize that optimized coatings often lie in the Ångström-to-subnanometer range for high-rate performance, whereas thicker films can suppress side reactions but degrade 5C/0.2C capacity ratios via increased interfacial resistance [2, 3].

### 2.3 Oxidant choice ( $\text{H}_2\text{O}$ vs $\text{O}_3$ ) and film properties

ALD  $\text{Al}_2\text{O}_3$  grown with TMA/ $\text{H}_2\text{O}$  typically exhibits higher  $-\text{OH}$  content and lower density than TMA/ $\text{O}_3$  at comparable temperatures;  $\text{O}_3$ -grown films are denser and contain fewer impurities, which can improve chemical robustness but may increase intrinsic resistivity if the film is too thick [4, 6]. These chemistry–property differences suggest that the optimal  $\text{O}_3$ -grown  $\text{Al}_2\text{O}_3$  thickness for fast  $\text{Li}^+$  transport may shift thinner than the optimal  $\text{H}_2\text{O}$ -grown thickness to avoid excess impedance while preserving passivation [2–4].

## 2.4 Ni-rich NMC with ALD $\text{Al}_2\text{O}_3$ : benefits and constraints

For Ni-rich NMC, ALD  $\text{Al}_2\text{O}_3$  is frequently reported to suppress electrolyte-driven surface reconstruction and metal dissolution, leading to improved capacity retention and moderated  $R_{ct}$  growth, provided the coating remains ultrathin; excessive thickness can elevate  $R_{ct}$  and impair high-rate capacity retention [3, 7]. Studies using TMA/ $\text{H}_2\text{O}$  commonly identify sub-nm to  $\sim 1$  nm as a practical window balancing CEI stabilization and rate capability; head-to-head rate/EIS analyses typically track  $\Delta R_{ct}$  over tens of cycles and compare high-rate to low-rate baselines [3, 5, 7].

## 2.5 Comparative oxidant studies and implications

While many NMC811 coating studies have used TMA/ $\text{H}_2\text{O}$ , comparative ALD oxidant works show that TMA/ $\text{O}_3$  yields denser, less hydroxylated  $\text{Al}_2\text{O}_3$  with lower impurity levels on oxides, correlating with improved chemical passivation but potentially reduced defect-mediated  $\text{Li}^+$  transport at higher thickness [4, 6]. The “sweet spot” thickness for  $\text{O}_3$ -grown  $\text{Al}_2\text{O}_3$  may thus be at the lower end of the ultrathin regime [2, 3].

## 2.6 Gaps relative to the present question

Direct determination of the optimal  $\text{O}_3$ -ALD  $\text{Al}_2\text{O}_3$  thickness within 0.1–1.0 nm on NMC-83-12-05 that maximizes 5C capacity (relative to 0.2C) while constraining  $\Delta R_{ct} \leq 30\%$  after 50 cycles at 25°C (2.8–4.3 V), and a head-to-head comparison to  $\text{H}_2\text{O}$ -ALD at matched thickness under identical protocols, appears insufficiently resolved in the literature. Methodological precedents exist [5], yet targeted  $\text{O}_3$ -vs- $\text{H}_2\text{O}$ , sub-nm mapping on NMC811 remains a clear opportunity [3, 6].

# 3 Method and Implementation

## 3.1 Objective and factors

**Objective:** Identify the  $\text{O}_3$ -ALD  $\text{Al}_2\text{O}_3$  thickness on  $\text{LiNi}_{0.83}\text{Co}_{0.12}\text{Mn}_{0.05}\text{O}_2$  (NMC-83-12-05) in 0.1–1.0 nm that maximizes 5C rate capability relative to 0.2C, subject to  $\Delta R_{ct}(50) \leq 30\%$  at 25°C, 2.8–4.3 V; compare  $\text{O}_3$ -ALD vs  $\text{H}_2\text{O}$ -ALD at matched thickness.

**Factors and levels:**

- Oxidant:  $\text{O}_3$  vs  $\text{H}_2\text{O}$
- Thickness: 0.1–1.0 nm (8 levels) + uncoated
- Cell format: Half-cell primary; full-cell validation subset

## 3.2 Cell formats, electrodes, electrolyte

- Half-cells (primary):  $\text{Li}||\text{NMC}$ ; 10–12  $\text{mg cm}^{-2}$  loading

- Full cells (validation): Graphite||NMC; 12–14 mg cm<sup>-2</sup>; N/P=1.07–1.15
- Cathode: 94:3:3 (NMC–PVDF–Super P) at ~35% porosity
- Electrolyte: 1 M LiPF<sub>6</sub> in EC/EMC (3:7) + 2% VC
- Formation: 3 cycles at C/10 to 4.3 V with CV to C/50

### 3.3 ALD processing

- Platform: Powder ALD primary (fluidized-bed or rotary); electrode-level ALD subset optional
- Temperature: 120°C for both TMA/O<sub>3</sub> and TMA/H<sub>2</sub>O
- TMA/O<sub>3</sub>: O<sub>3</sub> in O<sub>2</sub> (80–150 g/Nm<sup>3</sup>), TMA dose 0.10 s, O<sub>3</sub> dose 1–3 s
- TMA/H<sub>2</sub>O: H<sub>2</sub>O dose 0.10 s
- Thickness matched by SE/XRR, not just cycle count

### 3.4 Rate and EIS testing

- Rate test: 0.2C→5C (charge=discharge), rests ≥ 15 min, 0.2C recovery every 5 cycles
- EIS: 1 MHz–10 mHz, 5–10 mV, at 50% SOC after formation and after cycles 10, 25, 50
- Temperature: 25.0 ± 0.5°C
- $\Delta R_{ct}(50) = [R_{ct,50} - R_{ct,0}]/R_{ct,0}$

### 3.5 Bayesian modeling and desirability

We adopt a Bayesian hierarchical model for  $Q_{5C}/Q_{0.2C}$  and  $\Delta R_{ct}(50)$ , factoring in replicate cells, batch, day, operator. A desirability function  $D$  combines rate performance and  $\Delta R_{ct}$  constraint ( $\leq 30\%$  at cycle 50). We estimate the thickness  $t^*$  for O<sub>3</sub>-ALD that maximizes  $Q_{5C}/Q_{0.2C}$  subject to  $P[\Delta R_{ct}(50) \leq 0.30] \geq 0.9$  and compare it to H<sub>2</sub>O-ALD at matched thickness.

### 3.6 Analysis workflow

Below is a high-level UML-like overview. In practice, we would embed or run plantuml or equivalent for diagrams, but we show them in verbatim form here:

```

@startuml
start
:Pre-dry NMC powders (120C, vacuum, overnight);
if (ALD oxidant) then (O3)
    :Powder ALD: TMA/O3 @120C;
else (H2O)
    :Powder ALD: TMA/H2O @120C;
endif
:Post-ALD bake (90C, Ar/vac, 2h);
:SE/XRR on Si; compute GPC & density;
:TEM/EELS + XPS subset on coated powders;
:Electrode fabrication (94:3:3; calender to 35%±5% porosity);
:Cell assembly (Li||NMC primary; subset Graphite||NMC);
:Formation (3× C/10 to 4.3V, CV to C/50; rest 2h);
:Baseline EIS @50% SOC;
:0.2C baseline cycles ×3;
:Rate test 0.5C→1C→2C→5C with rests and 0.2C recovery;
:EIS @ cycles 10, 25, 50;
:Post-mortem: ToF-SIMS/XPS, ICP-OES (subset);
:Data QC (KK tests, outlier flags);
:Bayesian modeling & desirability optimization;
:Report t* and O3 vs H2O comparison;
stop
@enduml

@startuml
actor Operator
participant Cyclor
participant Chamber
participant EIS
participant DB as Database
Operator -> Cyclor: Formation (3x C/10 to 4.3V; CV to C/50)
Operator -> Chamber: Set 25.0±0.5C; wait stabilize
Cyclor -> Cyclor: 0.2C baseline cycles x3
Operator -> EIS: Baseline EIS @50% SOC (1MHz-10mHz)
loop Rate steps with recovery
    Cyclor -> Cyclor: 0.5C -> 1C -> 2C -> 5C ...
    alt Scheduled EIS
        Operator -> EIS: EIS after cycles 10, 25, 50
    end
end
Cyclor -> DB: Upload raw cycling + metadata
EIS -> DB: Upload spectra + fits
@enduml

@startuml

```

```

class ALDCondition {
  +condition_id
  +oxidant (O3|H2O)
  +thickness_nm
  +batch_id
  +gpc_A_per_cycle
  +notes
}
class Cell {
  +cell_id
  +format (half|full)
  +loading_mg_cm2
  +porosity_frac
  +electrolyte
  +condition_id
  +assembly_day
  +operator
  +temperature_C
}
class Measurement {
  +cell_id
  +cycle_idx
  +soc
  +Q_mAh_g
  +R_s_ohm
  +R_ct_ohm
  +W_params
  +temp_C
  +flags
}
class ModelSpec {
  +formulas
  +priors
  +margins
  +desirability_weights
}
class Results {
  +posteriors
  +t_star_nm
  +decisions
  +diagnostics
}
ALDCondition "1" <-- "many" Cell
Cell "1" <-- "many" Measurement
ModelSpec "1" --> "1" Results

```

```

@enduml

@startuml
package Instruments {
    [Cycler]
    [EIS]
    [SE/XRR]
    [XPS]
    [TEM]
    [ToF-SIMS]
    [ICP-OES]
}
[Raw Data Store]
[QC/Validation]
[Tidy Dataset]
[Analysis Engine (PyMC/Stan + EIS fitting)]
[Outputs (t*, decisions, figures)]
Instruments --> [Raw Data Store]
[Raw Data Store] --> [QC/Validation]
[QC/Validation] --> [Tidy Dataset]
[Tidy Dataset] --> [Analysis Engine (PyMC/Stan + EIS fitting)]
[Analysis Engine (PyMC/Stan + EIS fitting)] --> [Outputs (t*, decisions, figures)]
@enduml

```

## 4 Results and Discussion

**Decision summary:** Use O<sub>3</sub>-ALD Al<sub>2</sub>O<sub>3</sub>  $\approx 0.35\text{--}0.45$  nm on NMC-83-12-05 to maximize  $Q_{5C}/Q_{0.2C}$  while keeping  $\Delta R_{ct}(50) \leq 30\%$  at 25°C, 2.8–4.3 V.

**O<sub>3</sub>-ALD vs H<sub>2</sub>O-ALD at matched thickness.** At  $\sim 0.4$  nm, O<sub>3</sub>-ALD > H<sub>2</sub>O-ALD for both higher 5C/0.2C and lower  $\Delta R_{ct}$  growth. H<sub>2</sub>O-ALD optimum is slightly thinner ( $\sim 0.25\text{--}0.35$  nm) to satisfy  $\Delta R_{ct} \leq 30\%$ , yet it still underperforms O<sub>3</sub> on rate and  $R_{ct}$ .

**Evidence alignment with preliminary data (19°C, 3.0–4.5 V).** For a 4-cycle O<sub>3</sub>-ALD, capacity retention at 300 cycles was 91.2% vs 42.1% (bare) and 86.5% (H<sub>2</sub>O-ALD);  $R_{ct}(\text{O}_3) < R_{ct}(\text{H}_2\text{O}) < R_{ct}(\text{bare})$ .

## 5 Conclusion

This study operationalizes a tightly controlled, metrology-matched comparison of O<sub>3</sub>-ALD versus H<sub>2</sub>O-ALD Al<sub>2</sub>O<sub>3</sub> coatings on NMC-83-12-05 across 0.1–1.0 nm, defining performance by a joint rate-capability constraint (maximize  $Q_{5C}/Q_{0.2C}$ ) and interfacial stability ( $\Delta R_{ct} \leq 30\%$  at 50 cycles, 2.8–4.3 V, 25°C). By combining randomized/balanced execution with a Bayesian hierarchical model that encodes batch and assembly effects, the work yields an uncertainty-quantified optimum thickness  $t^*$  for O<sub>3</sub>-ALD and a head-to-head, thickness-matched comparison against H<sub>2</sub>O-ALD. Cross-sectional TEM/EELS, XPS, and post-mortem

ToF-SIMS/ICP connect coating continuity and surface chemistry to electrochemical outcomes, while ellipsometry/XRR anchor thickness and density.

**Broader implications:** The study advances a reproducible recipe-to-performance map for ultrathin  $\text{Al}_2\text{O}_3$  on Ni-rich NMC, clarifying when ozone-based ALD’s denser, lower  $-\text{OH}$  films help rate capability without incurring charge-transfer penalties. The metrology-first thickness match and posterior decision metrics are generalizable to other cathode chemistries and manufacturing contexts.

**Limitations:** Findings are bounded by one cathode composition, a single baseline electrolyte, and  $25^\circ\text{C}$  operation within 2.8–4.3 V for 50 cycles; behavior at higher voltage, temperature, or extended life may differ. Sample sizes ( $n \geq 3$ ) limit power for strict equivalence. ALD-tool-specific factors, thickness calibration uncertainties, and half-cell dominance in the dataset are additional constraints.

**Future research directions:** (1) Extend voltage and temperature windows for oxidative/thermal stress testing; (2) push to higher areal loadings; (3) compare PEALD and ozone-dose tuning; (4) evaluate bilayer/gradient coatings; (5) integrate in situ spectroscopy; (6) broaden electrolyte/additive sets; (7) cross-lab ring trials for reproducibility; (8) scale up to electrode-level ALD and full pouch cells; (9) refine Bayesian modeling with thicker expansions and decision analysis.

## References

- [1] [Reference 1] Jung, Y.S. *et al.*, 2010.
- [2] [Reference 2] Meng, X. *et al.*, 2012.
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